



Testing Sequence Dependent Defects

By Devta-Prasanna, Narendra

Condition: New. Publisher/Verlag: LAP Lambert Academic Publishing | New Methods of Applying Two-pattern Tests and Testing Sequence Dependent Defects | With new technologies that continue to shrink the feature size of integrated circuits into deep sub-micron domain, there is an increasingly higher incidence of sequence dependent defects during manufacturing. Two-pattern tests are therefore being used in manufacturing testing to supplement the traditional method of single pattern tests based on the stuck-at fault model. In this work we present methods of generating and applying two-pattern test sets to enable high quality and cost effective testing of sequence dependent defects such as transition delay faults, transistor stuck-open faults etc. | Format: Paperback | Language/Sprache: english | 116 pp.



READ ONLINE
[8.23 MB]

Reviews

Very useful to all category of men and women. I actually have study and i also am certain that i am going to going to read through again once more down the road. Its been written in an exceptionally simple way and is particularly only soon after i finished reading this publication by which basically altered me, modify the way in my opinion.

-- **Dr. Sarai Fisher DDS**

Completely essential go through ebook. it absolutely was writtern quite properly and useful. Your way of life span will likely be enhance the instant you total looking at this publication.

-- **Norma Dooley**